Application/Control No. Applicant(s)/Patent Under Reexamination TAKEI, HIROMITSU Examiner Nguyen N Hanh Applicant(s)/Patent Under Reexamination TAKEI, HIROMITSU Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

	U.S. PATENT DOCUMENTS							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification			
	Α	US-5,864,191	01-1999	Nagate et al.	310/156.54			
	В	US-6,177,745	01-2001	Narita et al.	310/156.53			
	С	US-						
	D	US-						
	Ē	US-						
	F	US-						
	G	US-						
	Н	US-		·				
	1	US-						
	J	US-						
	К	US-		·				
	L	US-						
	М	US-						

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-069698	03-2000	JAPAN	Matsuo et al.	H02K 15/03
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

NON-PATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	· V						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.